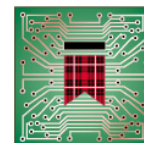


Reduction Of High-Frequency Signal Loss Through The Control Of Conductor Geometry And Surface Metallization

Don Cullen
MacDermid, Inc.
September 24th, 2002



MacDermid[®]
Printed Circuit Processing Technologies



Team Members

Gary Brist

PCB Technologist

Intel Corp. Hillsboro, OR

Don Cullen

Director - OEM & Assembly Applications

MacDermid Inc. Waterbury, CT

David Luttrull

Product Director - High Performance Materials

Park Nelco Tempe, AZ

John Martin

Hardware Engineering

Cisco Systems San Jose, CA

Magic?

..at a Price?

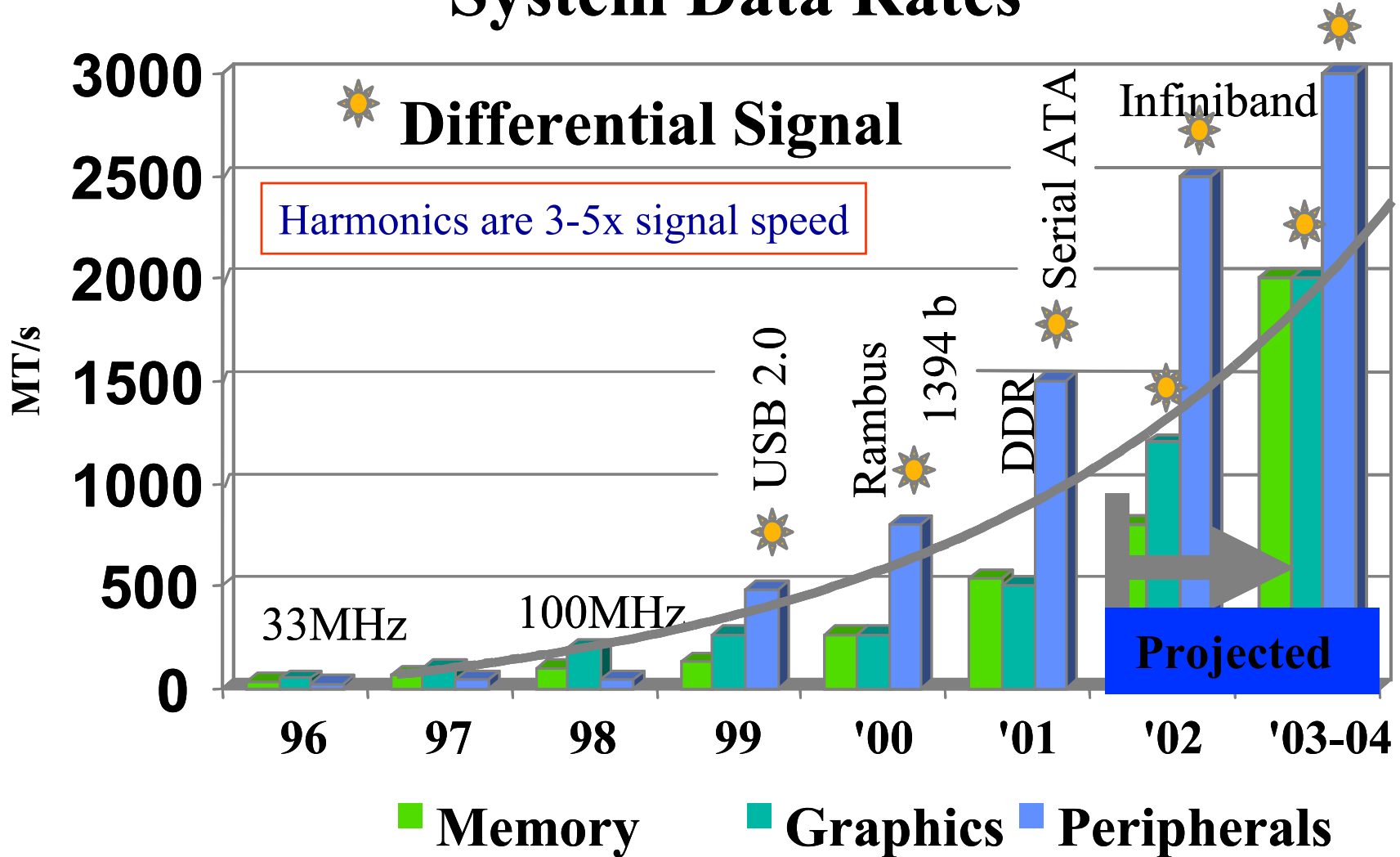


Drivers:

- Density
 - signal loss
- Environment
 - new materials
- Cost
 - old technology

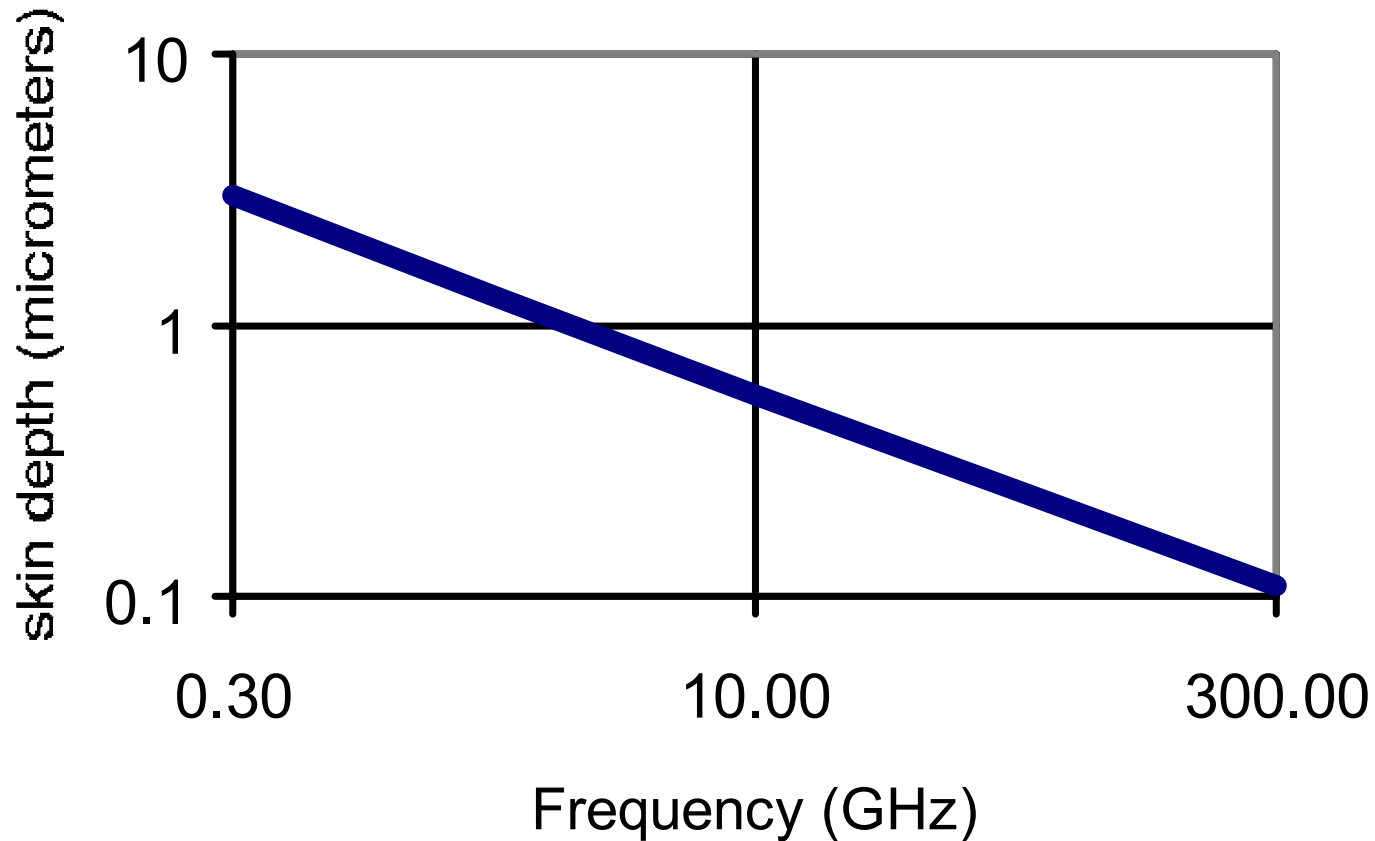
Speed!

System Data Rates



Skin Depth vs. Frequency

A.Scott; Understanding Microwaves



“...distance in the conductor at which the electric field has decreased to 30% of the value at the surface.”

Skin Depth Schematic



40 μ m

Copper Circuitry X-Section

Laminate Substrate

Skin Depth Schematic

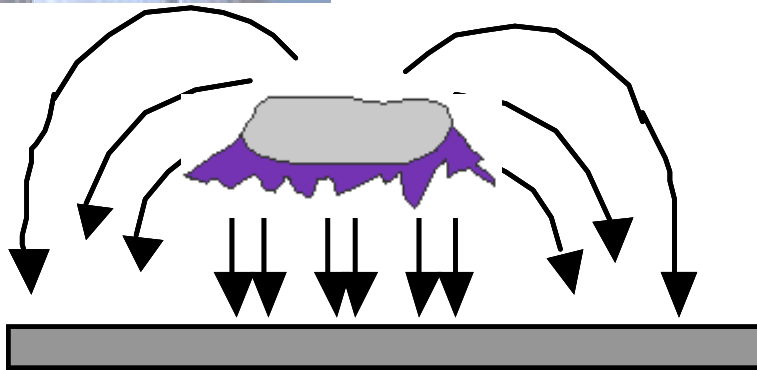


Ideal Shape is not Realistic

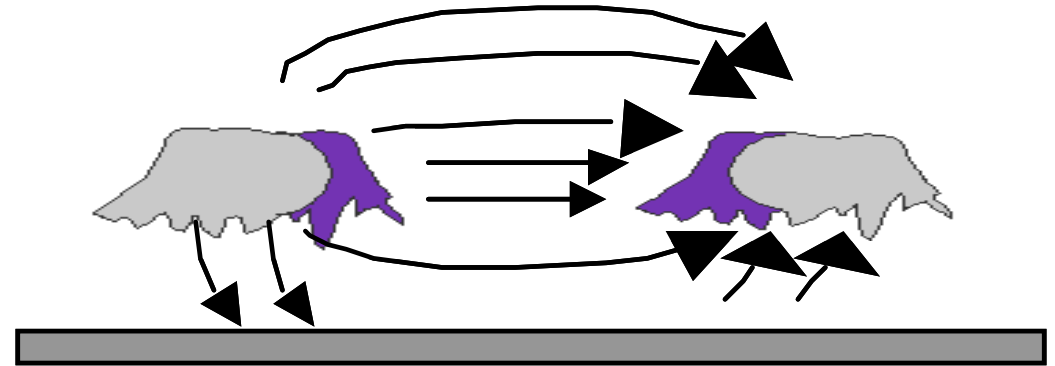
Skin Depth Schematic



Current Density by Design



SE microstrip



Differential

 High current density region

- Single Ended (SE) uStrip vs. Differential uStrip structures
 - Current densities and electric fields more concentrated in trace edges coated with surface finish
 - More sensitive to trace geometries

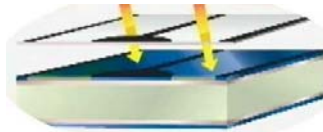
PCB Process Sequence



Clean Substrate



Innerlayer Resist



Expose/ Develop



Etch



Resist Strip



Innerlayer Oxide



Lamination



Drill



Desmear



Plate Thru Holes



Plating Resist



Electrolytic Copper



Tin Etch Resist



Strip Resist



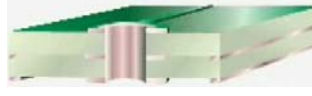
Outerlayer Etch



Tin Strip



Soldermask



Expose/ Develop/ Bake

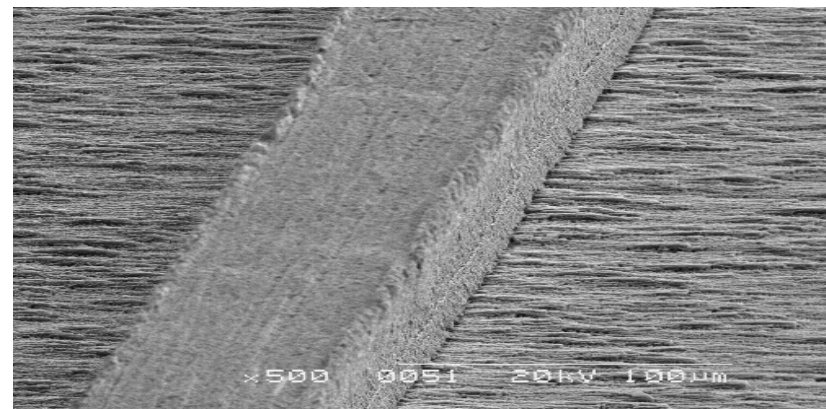
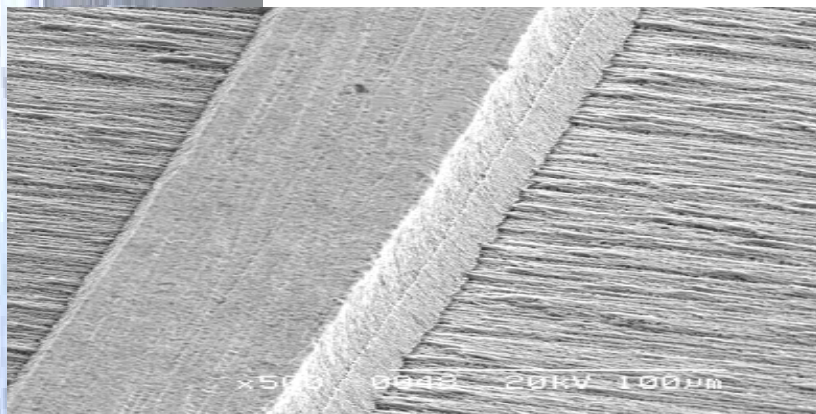
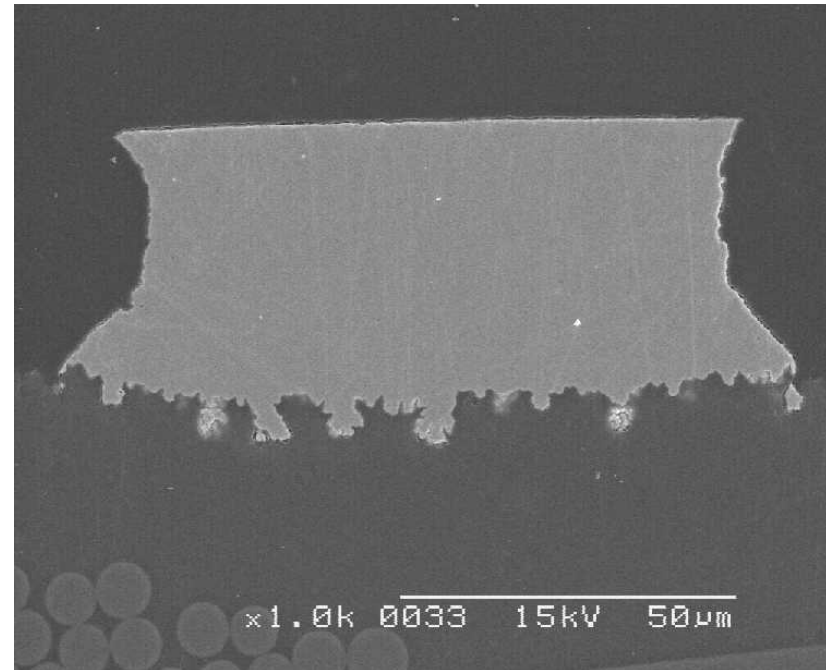
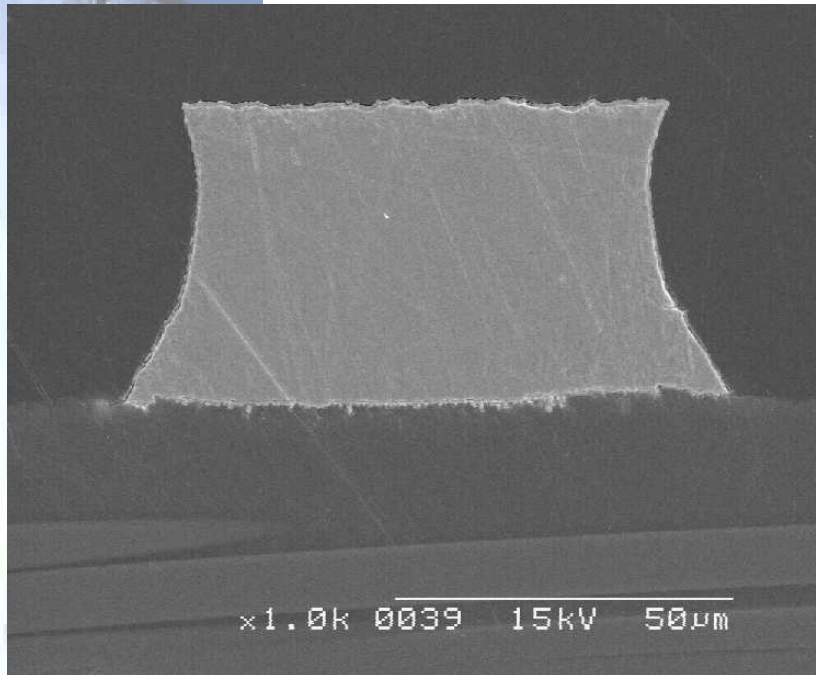


FINAL FINISH



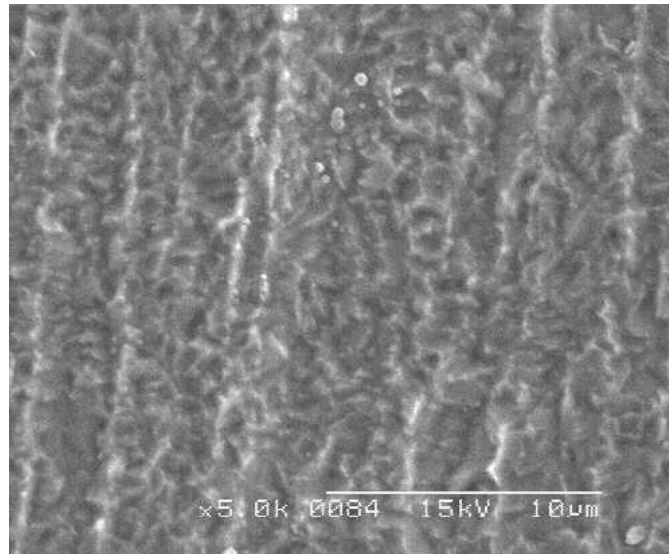
Legend Ink

Conductor Shape

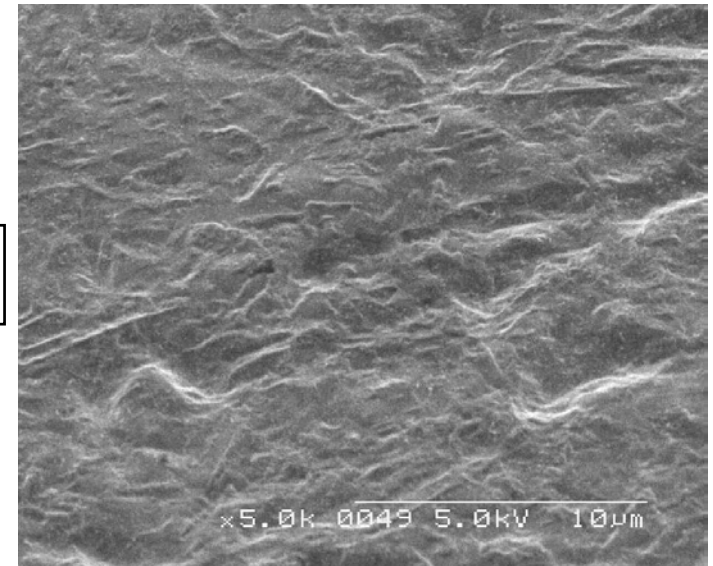


Surface Finish

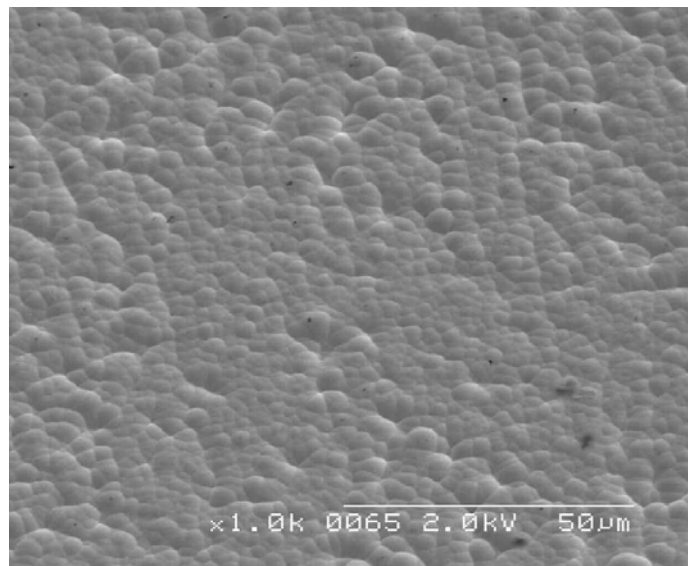
OSP



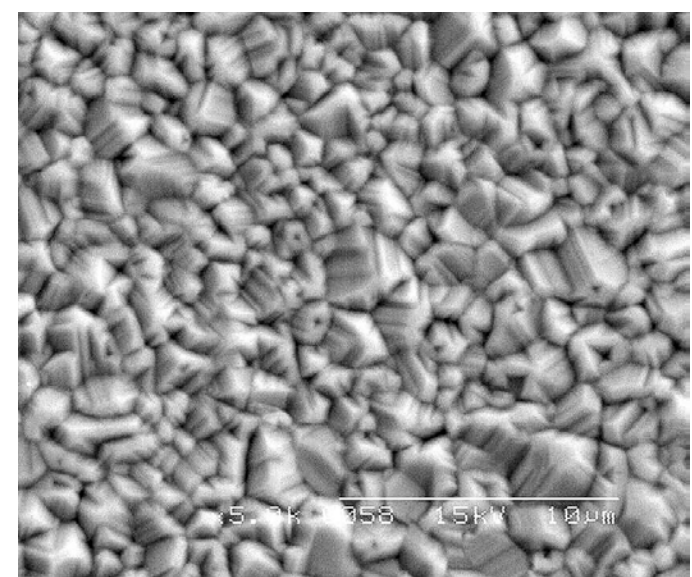
Ag



ENIG

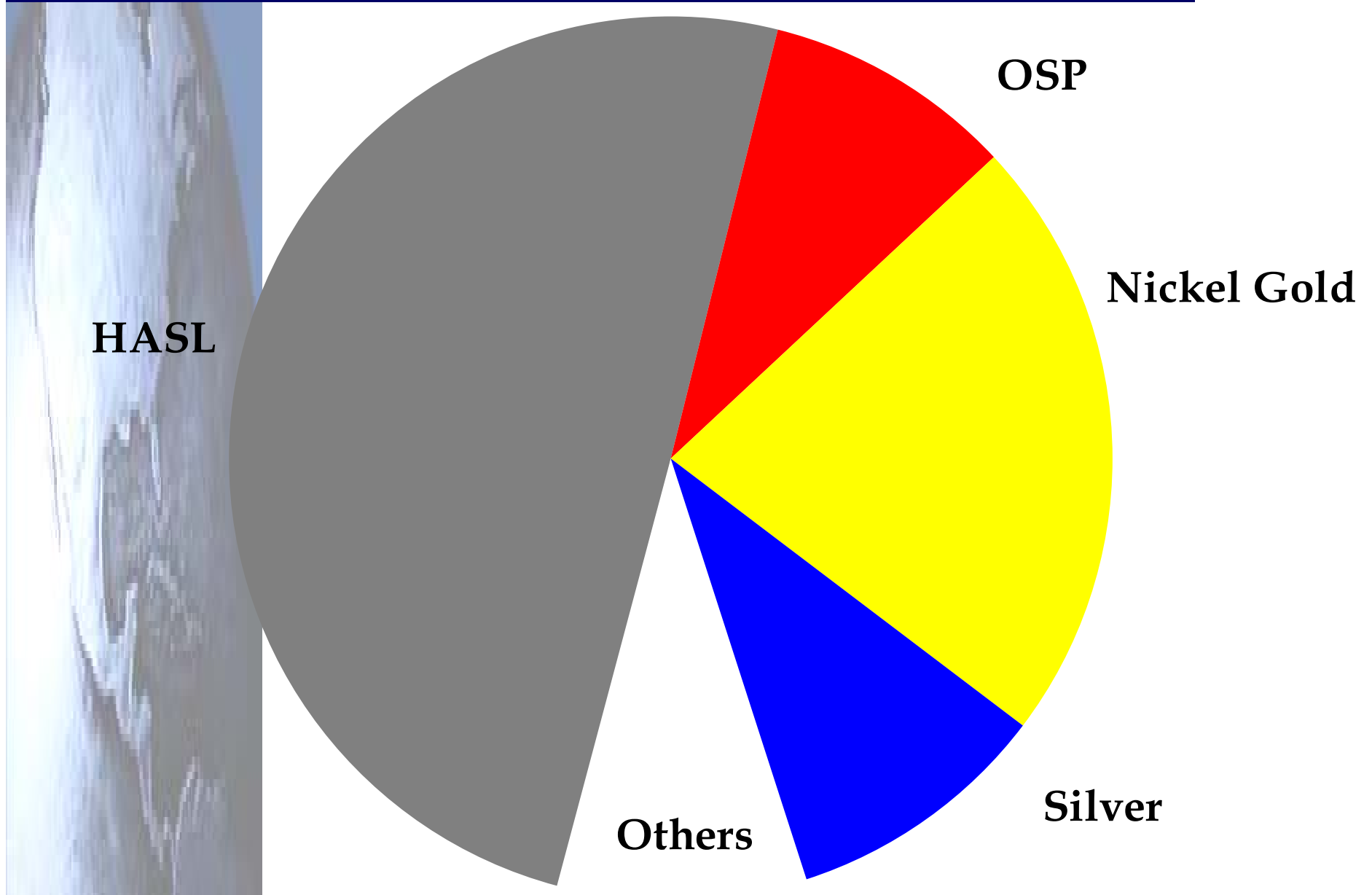


Sn



WW Use of Surface Finish

IPC Technology Marketing Research Council 2002



Metal Conductivity

Silver	1.6 $\mu\Omega\text{cm}$
Copper	1.7 $\mu\Omega\text{cm}$
Gold	2.4 $\mu\Omega\text{cm}$
Nickel	7.4 $\mu\Omega\text{cm}$
Tin	10.9 $\mu\Omega\text{cm}$
Sn60Pb40 solder	17.0 $\mu\Omega\text{cm}$
E-Less Ni P	55-90 $\mu\Omega\text{cm}$

Substrate Properties

Property	FR-4	Modified FR-4	APPE
	N-4000-6 FC	N-4000-13	N-6000-21
Permittivity *	4.0+/-0.1	3.6+/-0.1	3.5+/- 0.1
Permittivity**	4.3+/-0.1	4.0+/-0.1	3.9+/- 0.1
Dissipation Factor *	0.025	0.013	0.004
Dissipation Factor **	0.0140	0.0088	0.0085
Moisture Absorption	0.20%	0.10%	0.05%
Peel Strength lbs/inch	> 10.0	> 9.0	> 9.0
Flammability	94V-0	94V-0	94V-0

* by Stripline (IPC-TM-650) at 1.5 - 2.0 GHz.

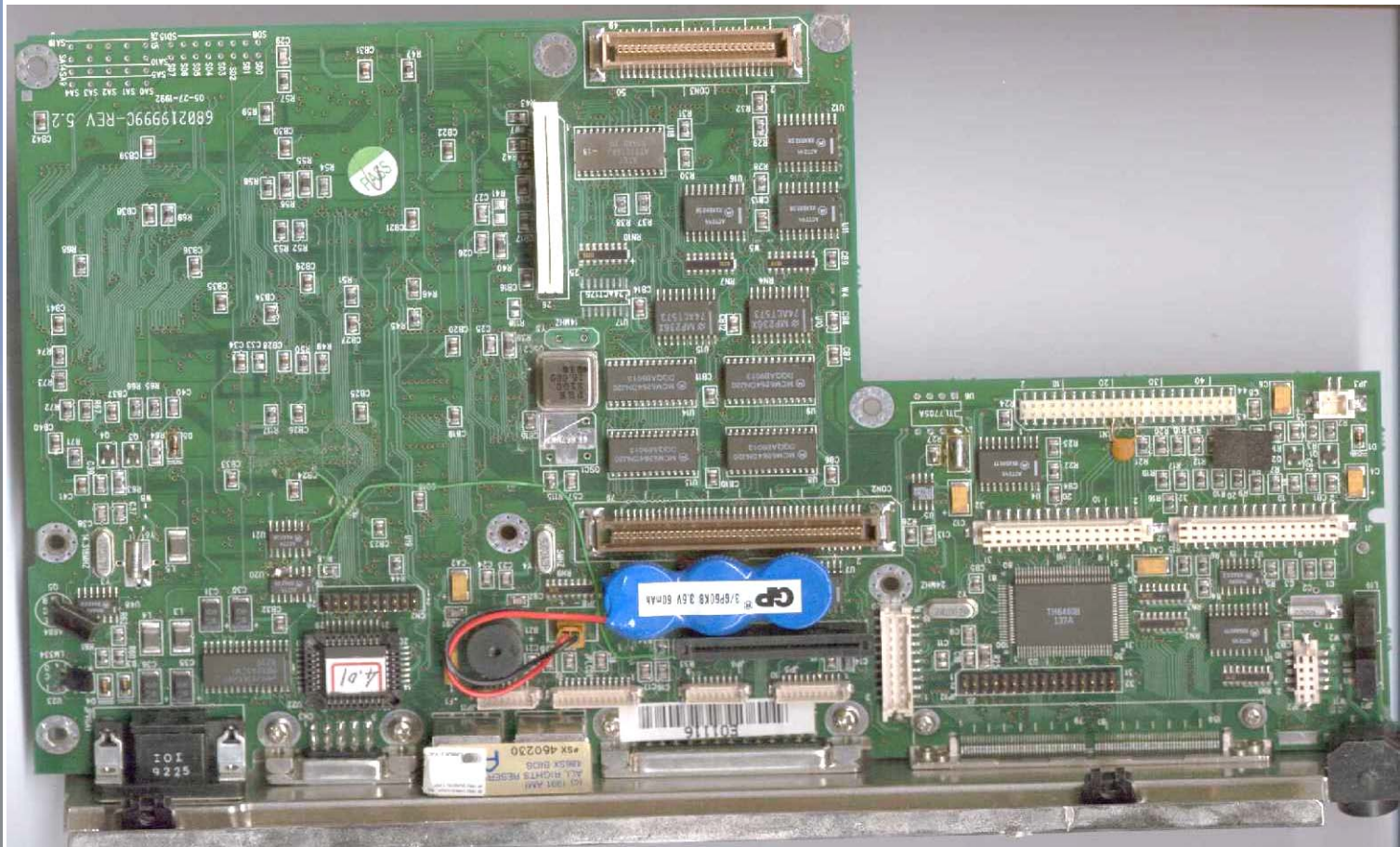
** by Split-Post Cavity Resonator (NIST) at 3.3 GHz.



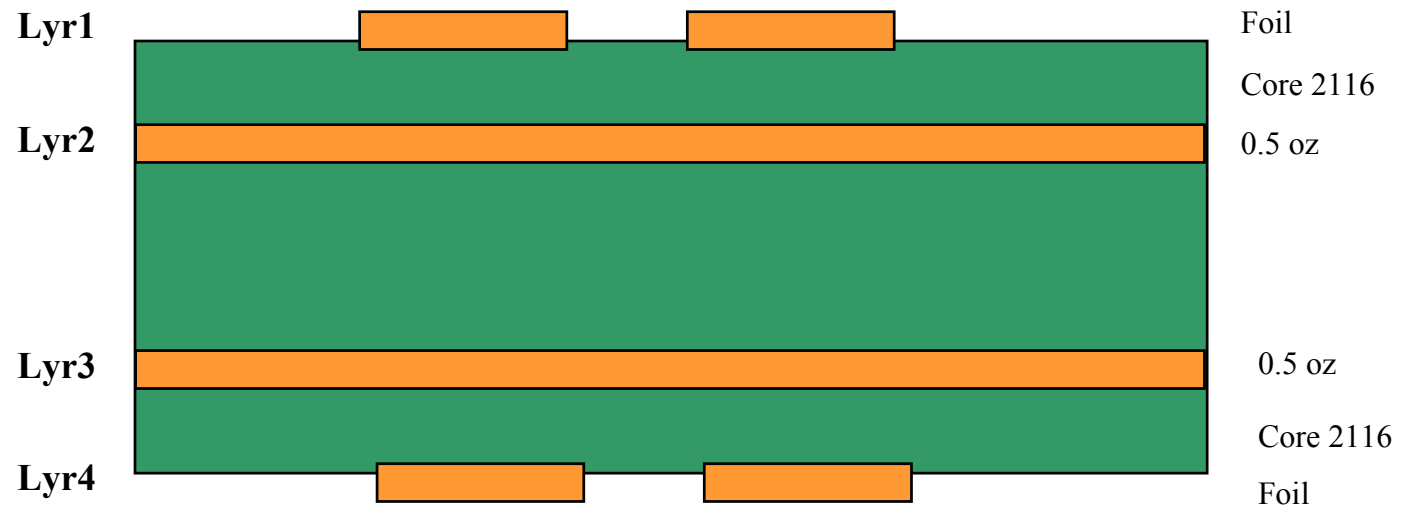
Experiment Matrix

- Substrate Material
 - N4000-6
 - N4000-13
 - N6000-21
- Foil Type
 - standard (ED)
 - reverse treat (RTF)
- Film Thickness and Etching
- Surface Finish
 - Organic Solderability Preservative
 - Electroless Nickel Immersion Gold
 - Immersion Silver
 - Immersion Tin
- Frequency

Experiment Goals



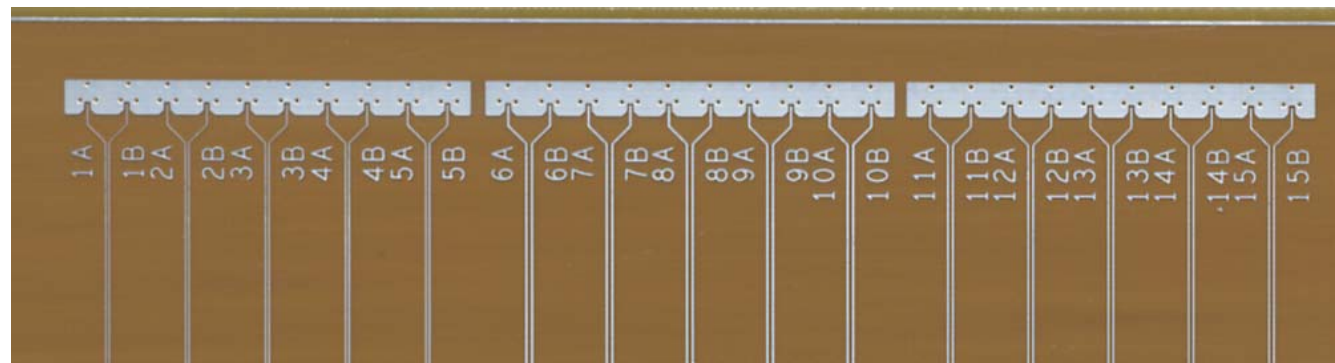
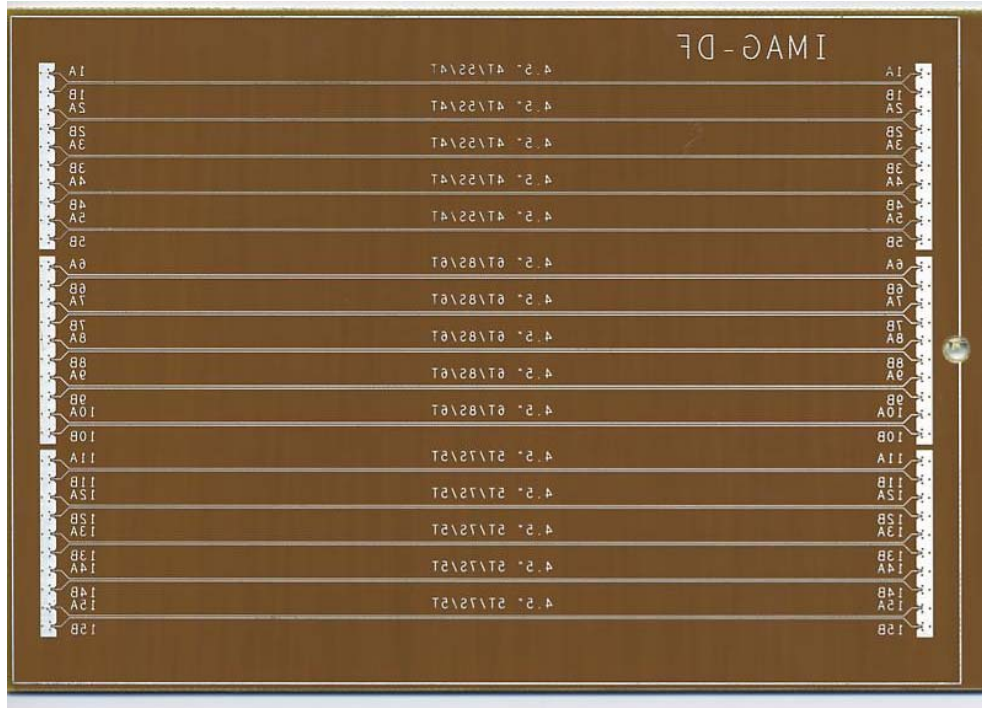
Test Vehicle



Total thickness 44-62mils

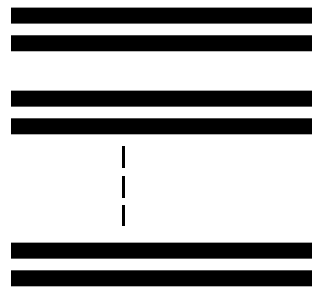
Conventional Core Lamination: thickness control, resin content control

Transmission Line Design

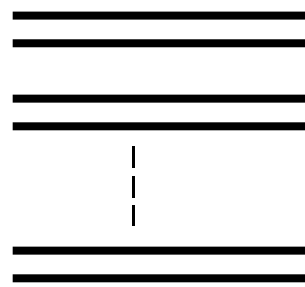


Coupon Design

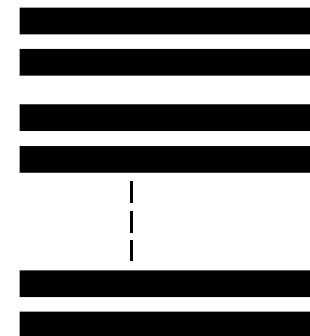
- 3 different line width/space combinations
 - Selected so that 1 line width targets $\sim 100\text{ohm}$ differential on a specific material
 - Allows comparison between similar line width vs similar Z_0 (characteristic impedance) target
- Repeat 3 width/space combinations 5 times within coupon
 - Correct for measurement variations
 - Encompass spatial variations due to glass weave issues.



Traces for Mtrl 1



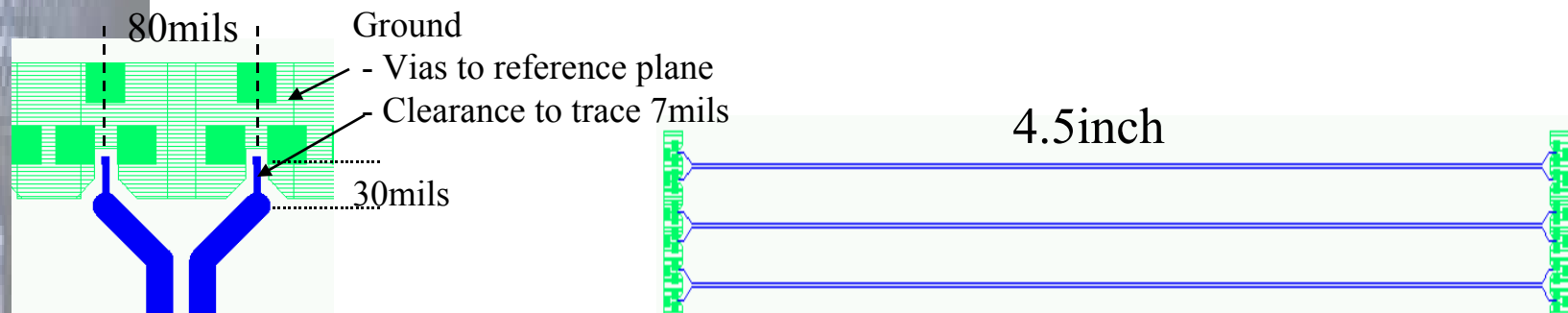
Traces for Mtrl 2



Traces for Mtrl 3

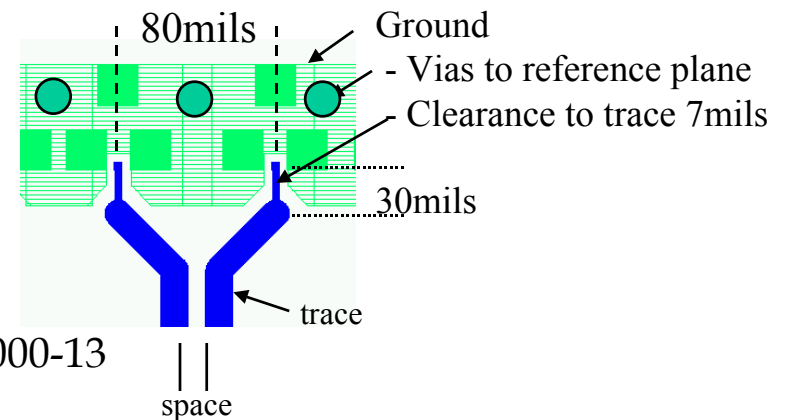
Coupon Design / Measurement

- Desire to not terminate in a connector
 - Utilize Cascade micro probe
 - Good through 18+GHz
 - Better for direct measurement for RLGC extractions
- Measurements to be taken coplanar
 - Sets up E-field as differential
 - Does not require 4port VNA



Coupon Design / Measurement

- Coupon Geometries
 - Dielectric Spacing (2116 core) ~4.2mils
 - Trace Pair A
 - Target 100ohm on N4000-6/N4000-13
 - 4mil trace/5mil space
 - Trace Pair B
 - Target 100ohm on N6000-21
 - 6mil trace/8mil space
 - Trace Pair C
 - Target 85ohm on N4000-6/N4000-13
 - 5mil trace/7mil space



Cascade Probe, Agilent VNA

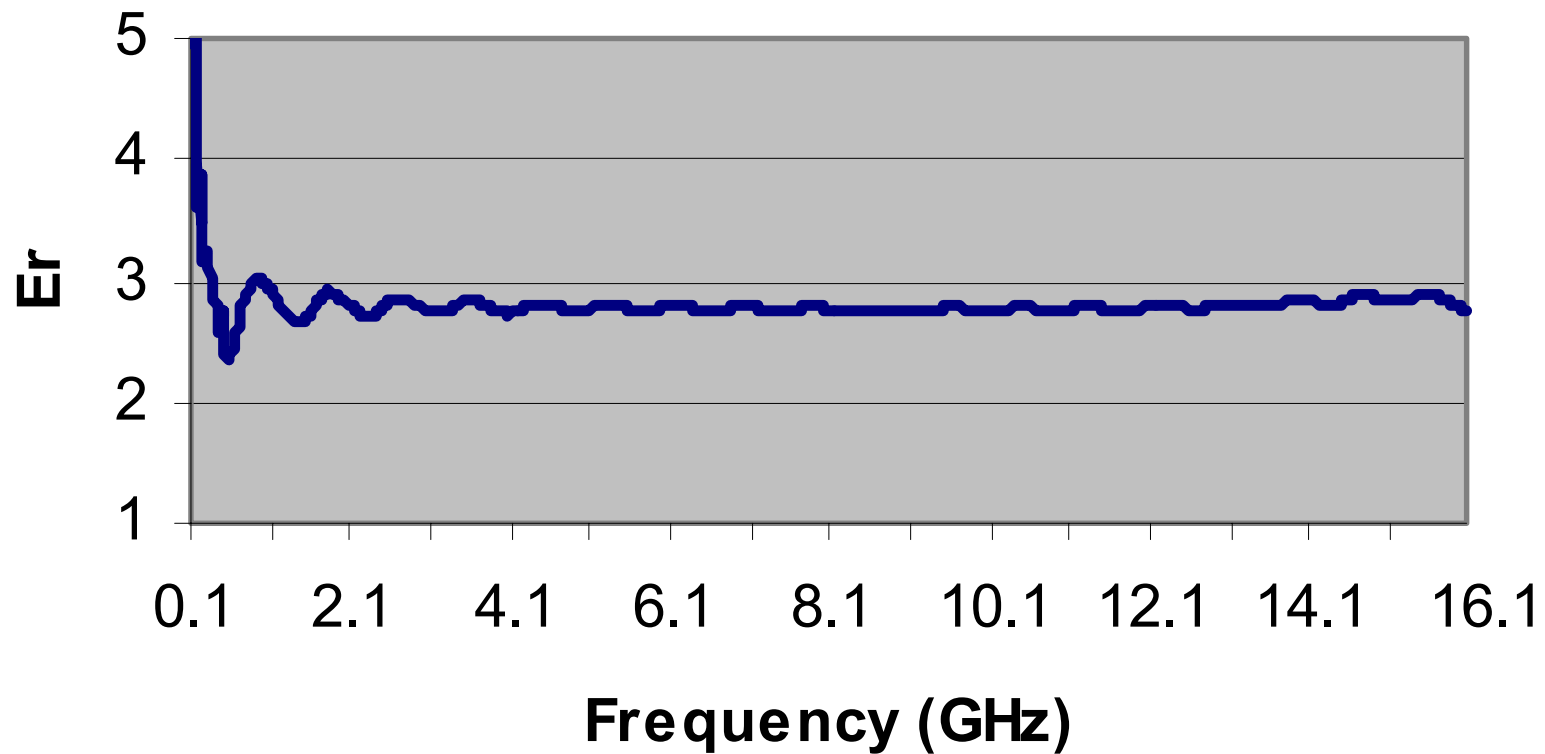


Responses

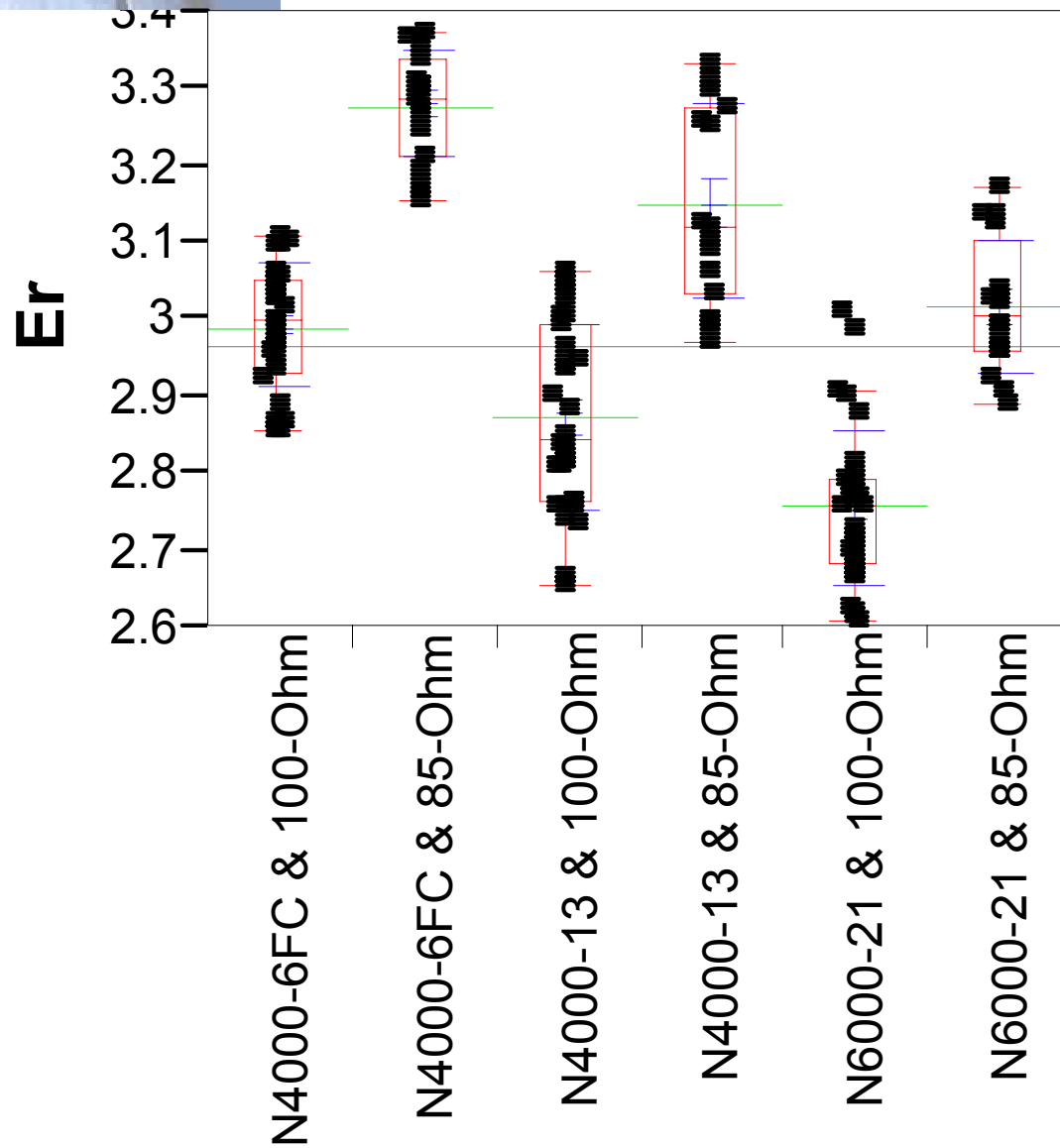
- Electrical analysis
 - S12 loss
 - Conductor loss (Extracted)
 - Differential Zo
 - Er dK (dielectric constant) from S12
- Mechanical
 - Line width
 - Conductor shape

Dielectric Constant is stable with Frequency

Effective ϵ_r (IMAG-Matrix 4,2)
(100MHz-16GHz)



Substrate Results

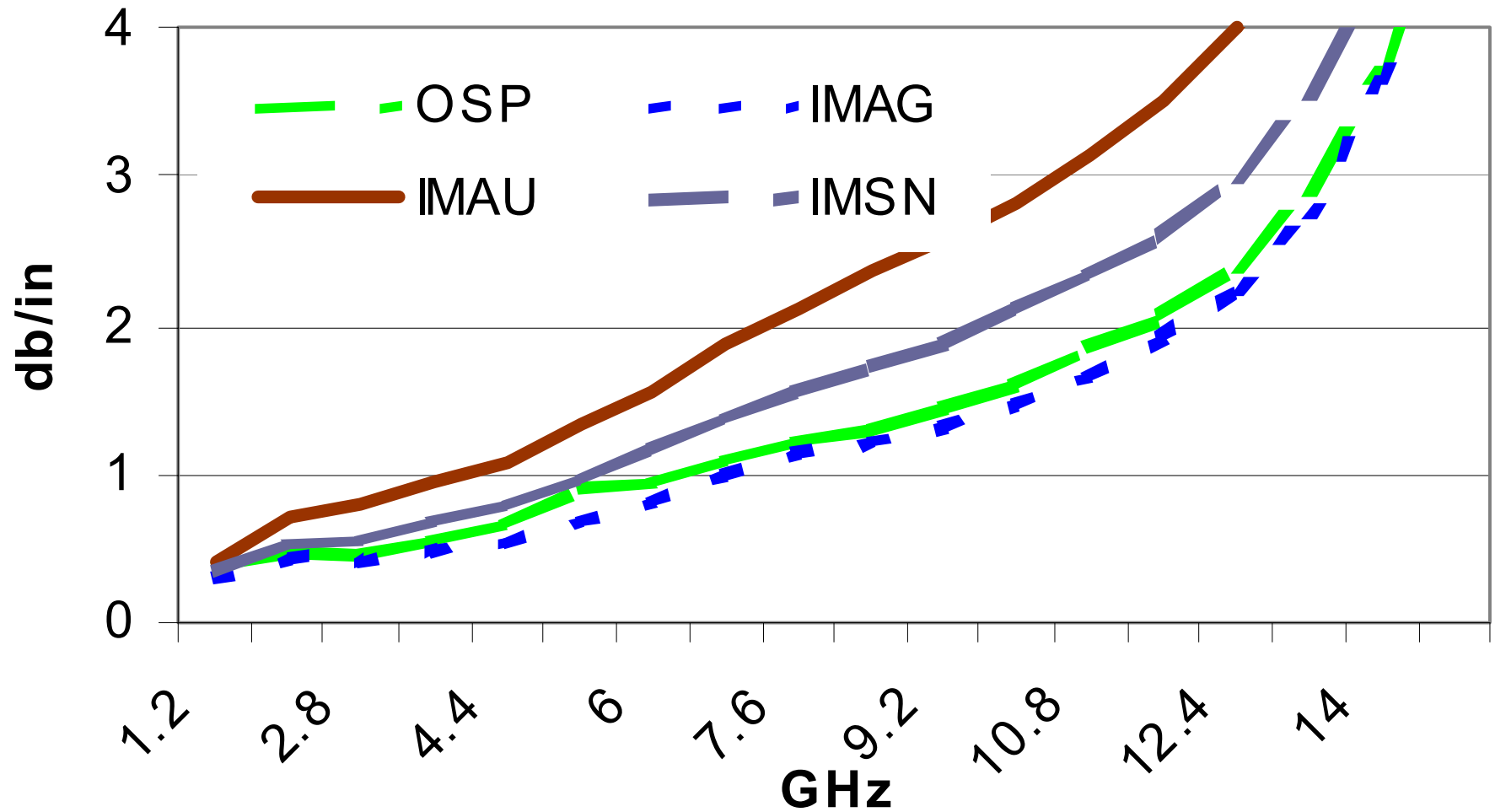


Note:

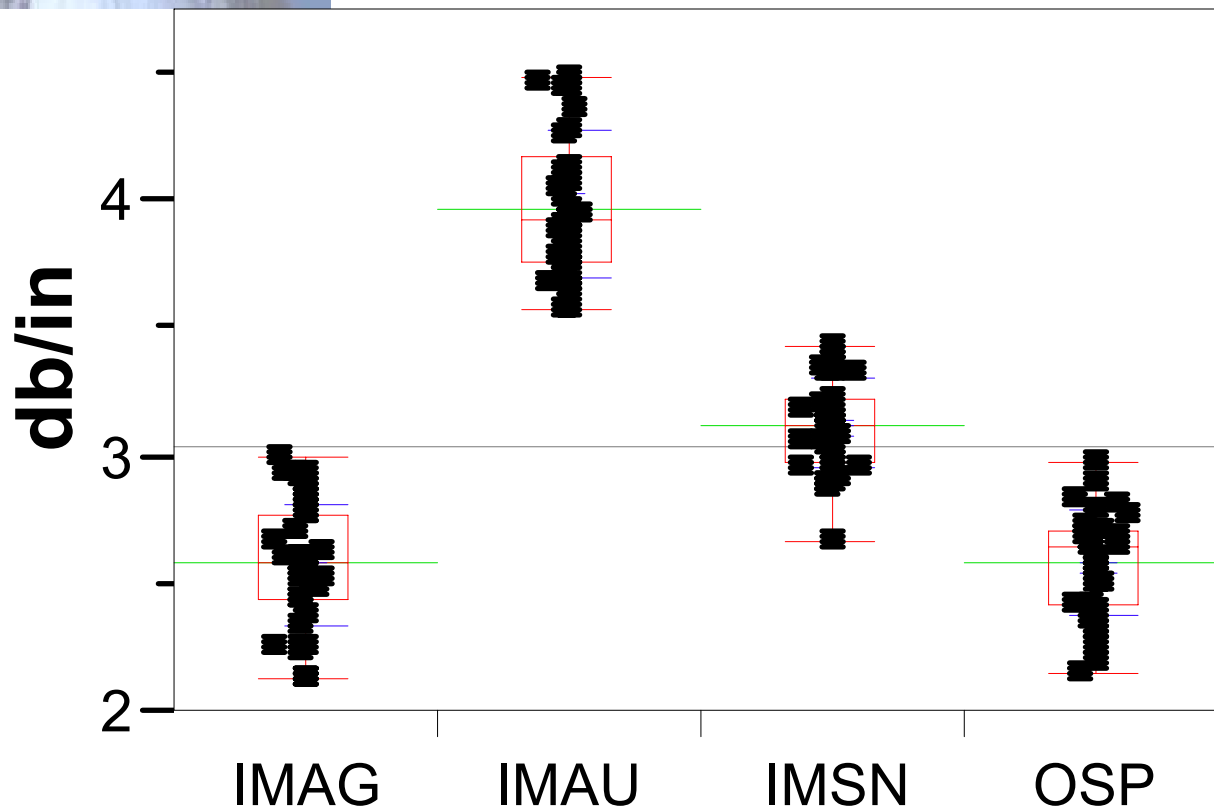
This is the “effective dielectric constant” of the system

- substrate
- air
- no soldermask

Across the Frequency Range



Surface Finish Results

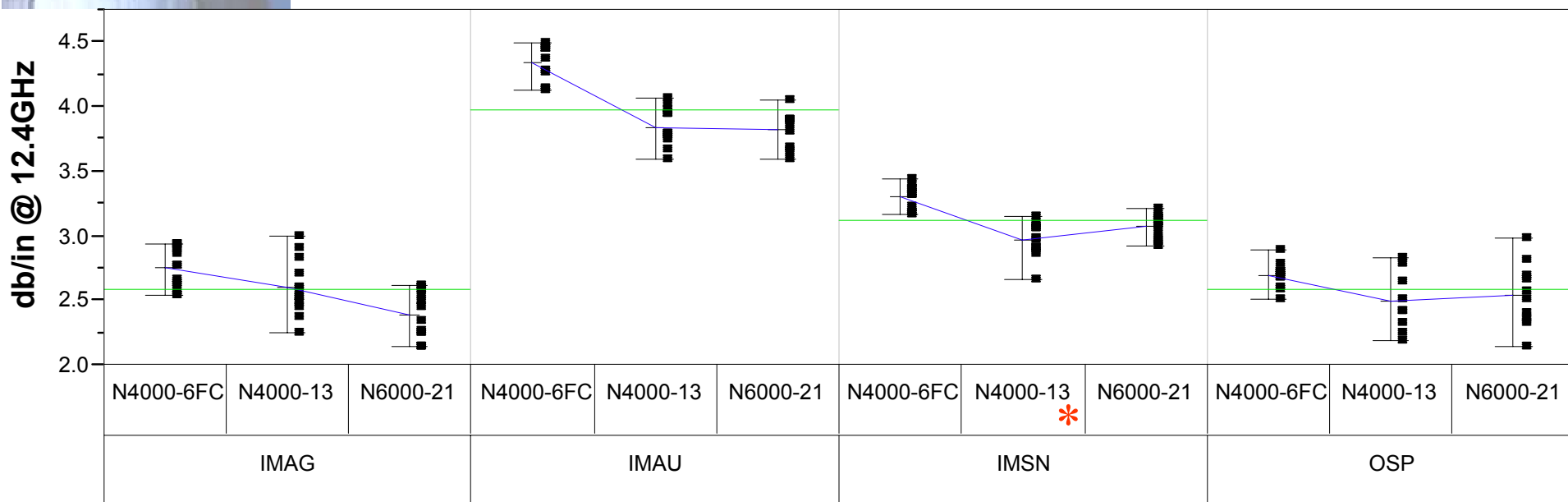


Note:

Expect higher loss from differential pair compared to microstrip designs

- no predominant ground return
- current crowding on traces

Loss by Finish and Material Type



Material within Surface Finish

* results chart shape affected by experimental error



Conclusions

- Frequency, as expected, gave the largest contribution to signal loss.
- Maximum loss occurred on the sample made from FR-4, standard tooth foil, poor conductor shape, ENIG.
- Foil tooth had a larger role than expected; study continues.
- Surface finish and foil tooth were more important with differential pair designs than with single-ended designs.
- Higher losses measure on ENIG and Sn followed predicted increases in bulk resistivity.



References

- A.Scott; Understanding Microwaves
- D.Cullen; RF Loss on Teflon Materials
- IPC TMRC, US EPA Surface Finishes
- J.McCall; Loss in Realistic PCB's
- D.Cullen; On the Surface - Circuitree
- MacDermid CD-Rom



Thank You